

SCCS053 - March 1997 - Revised March 2000

CY74FCT163373

16-Bit Latch

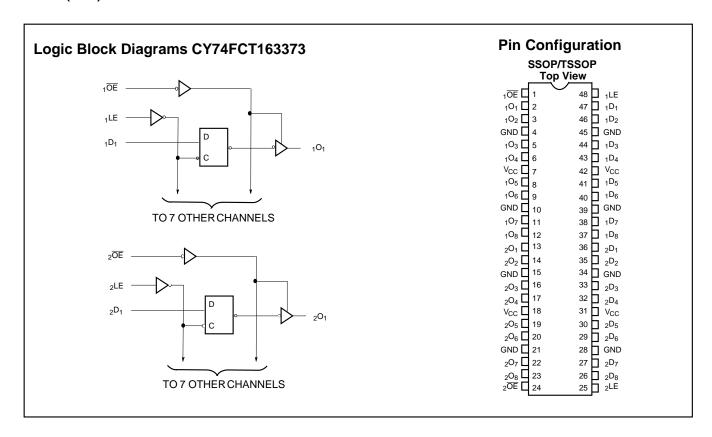
Features

- Low power, pin-compatible replacement for LCX and LPT families
- 5V tolerant inputs and outputs
- 24 mA balanced drive outputs
- Power-off disable outputs permits live insertion
- Edge-rate control circuitry for reduced noise
- FCT-C speed at 4.2 ns
- Latch-up performance exceeds JEDEC standard no. 17
- Typical output skew < 250 ps
- Industrial temperature range of -40°C to +85°C
- TSSOP (19.6-mil pitch) or SSOP (25-mil pitch)
- Typical V_{olp} (ground bounce) performance exceeds Mil Std 883D
- V_{CC} = 2.7V to 3.6V
- ESD (HBM) > 2000V

Functional Description

This device is a 16-bit, D-type latch, designed for use in bus applications requiring high speed and low power. It can either be used as two independent 8-bit latches, or as a single 16-bit latch by connecting the Output Enable (\overline{OE}) and Latch (LE) inputs. The outputs are 24-mA balanced output drivers with current limiting resistors to reduce the need for external terminating resistors and provide for minimal undershoot and reduced ground bounce. Flow-through pinout and small shrink packaging aid in simplifying board layout.

The CY74FCT163373 is designed with inputs and outputs capable of being driven by 5.0V buses, allowing its use in mixed voltage systems as a translator. The outputs are also designed with a power off disable feature enabling its use in applications requiring live insertion.





Pin Description

Name	Description		
D	Data Inputs		
LE	Latch Enable Inputs (Active HIGH)		
ŌĒ	Output Enable Inputs (Active LOW)		
0	Three-State Outputs		

Function Table^[1]

	Outputs		
D	LE	ŌĒ	0
Н	Н	L	Н
L	Н	L	L
Х	L	L	Q_0
Х	Х	Н	Z

Maximum Ratings^[2, 3]

(Above which the useful life may guidelines, not tested.)	y be impaired. For user
Storage Temperature	55°C to +125°C
Ambient Temperature with Power Applied	55°C to +125°C
Supply Voltage Range	0.5V to +4.6V
DC Input Voltage	0.5V to +7.0V
DC Output Voltage	0.5V to +7.0V
DC Output Current (Maximum Sink Current/Pin)	60 to +120 mA
Power Dissipation	1.0W

Operating Range

Range	Ambient Temperature	V _{CC}	
Industrial	–40°C to +85°C	2.7V to 3.6V	

Electrical Characteristics for Non Bus Hold Devices Over the Operating Range V_{CC}=2.7V to 3.6V

Parameter	Description	Test Conditions	Min.	Typ. ^[4]	Max.	Unit
V _{IH}	Input HIGH Voltage	All Inputs	2.0		5.5	V
V _{IL}	Input LOW Voltage				0.8	V
V _H	Input Hysteresis ^[5]			100		mV
V _{IK}	Input Clamp Diode Voltage	V _{CC} =Min., I _{IN} =-18 mA		-0.7	-1.2	V
I _{IH}	Input HIGH Current	V _{CC} =Max., V _I =5.5			±1	μΑ
I _{IL}	Input LOW Current	V _{CC} =Max., V _I =GND			±1	μΑ
I _{OZH}	High Impedance Output Current (Three-State Output pins)	V _{CC} =Max., V _{OUT} =5.5V			±1	μА
I _{OZL}	High Impedance Output Current (Three-State Output pins)	V _{CC} =Max., V _{OUT} =GND			±1	μА
Ios	Short Circuit Current ^[6]	V _{CC} =Max., V _{OUT} =GND	-60	-135	-240	mA
I _{OFF}	Power-Off Disable	V _{CC} =0V, V _{OUT} ≤4.5V			±100	μΑ
I _{CC}	Quiescent Power Supply Current	$V_{\text{IN}} \leq 0.2 \text{V},$ $V_{\text{CC}} = \text{Max}.$		0.1	10	μА
Δl _{CC}	Quiescent Power Supply Current (TTL inputs HIGH)	$V_{IN}=V_{CC}-0.6V^{[7]}$ $V_{CC}=Max$.		2.0	30	μА

Note:

- 1. H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care. Z = High Impedance. Q₀=Previous state of flip-flop.
- Operation beyond the limits set forth may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature With the exception of inputs with bus hold, unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground. Typical values are at V_{CC} =3.3V, T_A = +25°C ambient.

- This parameter is specified but not tested.
- Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
- 7. Per TTL driven input; all other inputs at V_{CC} or GND.



Electrical Characteristics For Balanced Drive Devices Over the Operating Range V_{CC} =2.7V to 3.6V

Parameter	Description	Test Conditions	Min.	Тур. ^[4]	Max.	Unit
I _{ODL}	Output LOW Dynamic Current ^[6]	V_{CC} =3.3V, V_{IN} = V_{IH} or V_{IL} , V_{OUT} =1.5V	45		180	mA
I _{ODH}	Output HIGH Dynamic Current ^[6]	V_{CC} =3.3V, V_{IN} = V_{IH} or V_{IL} , V_{OUT} =1.5V	-45	_	-180	mA
V _{OH}	Output HIGH Voltage	V _{CC} =Min., I _{OH} = -0.1 mA	V _{CC} -0.2			V
		V _{CC} =Min., I _{OH} = -8 mA	2.4 ^[8]	3.0		V
		V _{CC} =3.0V, I _{OH} = -24 mA	2.0	3.0		V
V _{OL}	Output LOW Voltage	V _{CC} =Min., I _{OL} = 0.1mA			0.2	V
		V _{CC} =Min., I _{OL} = 24 mA		0.3	0.55	

Note:

$\textbf{Capacitance}^{[5]}(T_{A} = +25^{\circ}C, \, f = 1.0 \; \text{MHz})$

Parameter	Description	Test Conditions	Typ. ^[4]	Max.	Unit
C _{IN}	Input Capacitance	$V_{IN} = 0V$	4.5	6.0	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	5.5	8.0	pF

Power Supply Characteristics

Parameter	Description	Test Condition	Test Conditions			Unit
I _{CCD}	Dynamic Power Supply Current ^[9]	V _{CC} =Max., One Input Toggling, 50% Duty Cycle, Outputs Open, OE=GND	V _{IN} =V _{CC} or V _{IN} =GND	50	75	μA/MHz
I _C	Total Power Supply Current ^[10]	V _{CC} =Max., f ₁ =10 MHz, 50% Duty Cycle, Outputs Open,	V _{IN} =V _{CC} or V _{IN} =GND	0.5	0.8	mA
		One Bit Toggling, OE=GND	V _{IN} =V _{CC} -0.6V or V _{IN} =GND	0.5	0.8	mA
		V _{CC} =Max., f ₁ =2.5 MHz, 50% Duty Cycle, Outputs Open, Sixteen Bits Toggling, \overrightarrow{OE} =GND	V _{IN} =V _{CC} or V _{IN} =GND	2.0	3.0 ^[11]	mA
			V _{IN} =V _{CC} -0.6V or V _{IN} =GND	2.0	3.3 ^[11]	mA

^{8.} $V_{OH}=V_{CC}-0.6 \text{ V}$ at rated current.



Switching Characteristics Over the Operating Range V_{CC} =3.0V to 3.6V^[12,13]

		CY74FCT163373C			
Parameter	Description	Min.	Max.	Unit	Fig. No. ^[14]
t _{PLH}	Propagation Delay D to Q Output	1.5	4.1	ns	1, 3
t _{PLH} t _{PHL}	Propagation Delay LE to Q Output	2.0	5.5	ns	1, 5
t _{PZH} t _{PZL}	Output Enable Time	1.5	5.8	ns	1, 7, 8
t _{PHZ}	Output Disable Time	1.5	5.2	ns	1, 7, 8
t _{SU}	Input Setup time	2.0	-	ns	1, 4
t _H	Input Hold time	1.5	-	ns	1, 4
t _{SK(O)}	Output Skew ^[15]		0.5	ns	_

I_{CCD} = Dynamic Current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero

= Input signal frequency

= Number of inputs changing at f₁

- All currents are in milliamps and all frequencies are in megahertz.

 Values for these conditions are examples of the I_{CC} formula. These limits are specified but not tested.
- Minimum limits are specified but not tested on Propagation Delays. For V_{CC} =2.7, propagation delay, output enable and output disable times should be degraded by 20%.
- See "Parameter Measurement Information" in the General Information section.
 Skew between any two outputs of the same package switching in the same direction. This parameter is ensured by design.

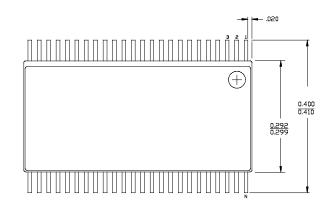
Ordering Information CY74FCT163373

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.2	CY74FCT163373CPACT	Z48	48-Lead (240-Mil) TSSOP	Industrial
	CY74FCT163373CPVC/PVCT	O48	48-Lead (300-Mil) SSOP	

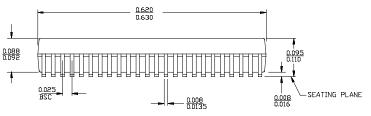


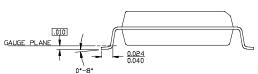
Package Diagrams

48-Lead Shrunk Small Outline Package O48

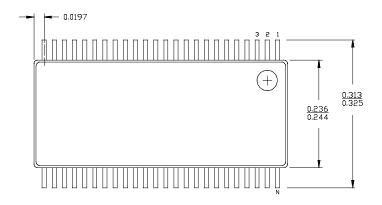


DIMENSIONS IN INCHES MIN. MAX.

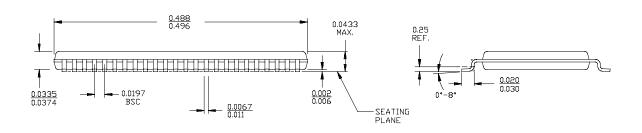




48-Lead Thin Shrunk Small Outline Package Z48



DIMENSIONS IN INCHES MIN. MAX.



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